How Low Can You Go? Exploring the Lower Limit of Crystal Size on a Home X-ray Source

J Ferrara¹, M Meyer², T Satow³, F White⁴, A Yamano⁵, T Matsumoto⁶
¹Rigaku Americas Corp, The Woodlands, TX, ²Rigaku Polska Sp. z o.o., Wroclaw, Poland, ³Rigaku Corporation, Tokyo, Japan, ⁴Rigaku Europe SE, Neu-Iksenbug, Germany, ⁵Application Laboratories, Rigaku Corporation, ⁶Rigaku Corp., Akishima, Japan

joseph.ferrara@rigaku.com

There is a misconception in the literature (Gruene, [i]et. al.[/i], 2018) that one needs crystals as large as 50 µm on a side to perform single X-ray diffraction studies. It has also been suggested that MicroED measurements are needed to probe smaller samples. In this presentation, we will demonstrate that this is simply not true. Furthermore, we will show the lower limit of what is possible with a home X-ray source is somewhere just above the upper range of what is accessible to MicroED, that is, about 1-3 µm.

We will also compare some X-ray and ED structural quality and make some suggestions regarding classification of different types of structures based on quality of the results.